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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/802,735	TAKAFUJI ET AL.	
Examiner	Art Unit	
Thien F. Tran	2811	

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Class	Subclass	Date	Examiner
257	59, 64, 66, 69, 70, 72, 347	8/1/2006	π
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